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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10024930	12/19/2001	250		2878	

****APPLICANTS:** Madsen Ian; Scarlett Nicola; Manias Constantine; Retallack David;
Schneider Karl;

****CONTINUING DATA VERIFIED:**
THIS APPLICATION IS A CON OF PCT/AU00/00697 06/21/2000

**** FOREIGN APPLICATIONS VERIFIED:**
AUSTRALIA PQ1094 06/21/1999

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		POF 3.9-050 CONT
Verified and Acknowledged Examiners's initials		
TITLE : Method and apparatus for X-ray diffraction analyses		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

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NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.
<input type="checkbox"/> TERMINAL		PREPARED FOR ISSUE	Application Examiner	